Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/719,874	SATOH, TOMIO	
Examiner	Art Unit	
David Mis	2817	

SEARCHED							
Class	Subclass	Date	Examiner				
331	36C, 115,	5/10/2005	DM				
	116R,						
	116FE,	,					
	132, 158,						
	159, 175,						
	177V						
	,						

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
as	above	5/10/2005	DM			
	<u> </u>					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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